

ABSTRACT

A method and apparatus for measuring inductance. The method and apparatus include processing current and voltage waveform data associated with an inductive device to determine edge and slope parameters for each of a plurality of current waveform data cycles. Furthermore, proportional magnetic flux and proportional magnetic current is determined from the acquired current waveform data and the voltage waveform data proximate determined edge regions of the waveform data. An inductance value of the inductive device may then be calculated from the proportional magnetic flux and proportional magnetic current.